

**DATA SHEET** 

#### PRODUCT DISCONTINUATION NOTICE - LAST TIME BUY EXPIRES JANUARY 27, 2015

### **General Description**

The ICS874003-04 is a high performance Differential-to-LVDS Jitter Attenuator designed for use in PCI Express systems. In some PCI Express systems, such as those found in desktop PCs, the PCI Express™ clocks are generated from a low bandwidth, high phase noise PLL frequency synthesizer. In these systems, a jitter attenuator may be required to attenuate high frequency random and deterministic jitter components from the PLL synthesizer and from the system board. The ICS874003-04 has a bandwidth of 6.8MHz. The 6.8MHz provides a high bandwidth that can easily track triangular spread profiles, while providing jitter attenuation.

The ICS874003-04 uses IDT's 3<sup>rd</sup> Generation FemtoClock™ PLL technology to achieve the lowest possible phase noise. The device is packaged in a 20 Lead TSSOP package, making it ideal for use in space constrained applications such as PCI Express add-in cards.

#### **Features**

- Three differential LVDS output pairs
- · One differential clock input
- CLK/nCLK can accept the following differential input levels: LVPECL, LVDS, LVHSTL, HCSL, SSTL
- Input frequency range: 98MHz to 128MHz
- Output frequency range: 98MHz to 320MHz
- VCO range: 490MHz 640MHz
- Supports PCI-Express Spread-Spectrum Clocking
- · High PLL bandwidth allows for better input tracking
- Full 3.3V supply mode

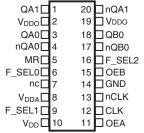
1

- 0°C to 70°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages
- Use replacement part: 874003BG-05LF

#### F\_SEL[2:0] Function Table

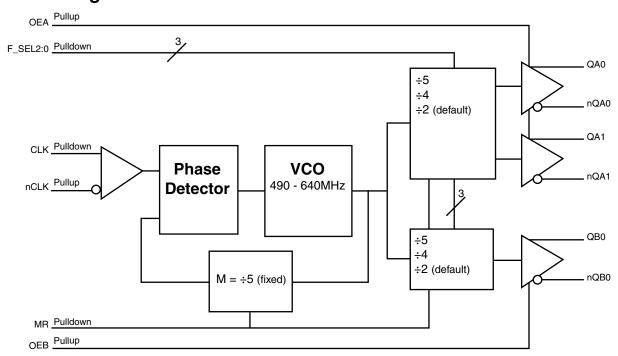
Inputs			Outputs		
F_SEL2	F_SEL1	F_SEL0	QA[0:1], nQA[0:1]	QB, nQB0	
0	0	0	÷2	÷2	
1	0	0	÷5	÷2	
0	1	0	÷4	÷2	
1	1	0	÷2	÷4	
0	0	1	÷2	÷5	
1	0	1	÷5	÷4	
0	1	1	÷4	÷5	
1	1	1	÷4	÷4	

### **Pin Assignment**



ICS874003-04
20-Lead TSSOP
6.5mm x 4.4mm x 0.925mm package body
G Package
Top View

# **Block Diagram**



**Table 1. Pin Descriptions** 

Number	Name	T	уре	Description
1, 20	QA1, nQA1	Output		Differential output pair. LVDS interface levels.
2, 19	$V_{DDO}$	Power		Output supply pins.
3, 4	QA0, nQA0	Output		Differential output pair. LVDS interface levels.
5	MR	Input	Pulldown	Active HIGH Master Reset. When logic HIGH, the internal dividers are reset causing the true outputs (Qx) to go low and the inverted outputs (nQx) to go high. When logic LOW, the internal dividers and the outputs are enabled. LVCMOS/LVTTL interface levels.
6, 9, 16	F_SEL0, F_SEL1, F_SEL2	Input	Pulldown	Frequency select pin for QAx, nQAx and QB0, nQB0 outputs. LVCMOS/LVTTL interface levels.
7	nc	Unused		No connect.
8	$V_{DDA}$	Power		Analog supply pin.
10	V <sub>DD</sub>	Power		Core supply pin.
11	OEA	Input	Pullup	Output enable pin for QA pins. When HIGH, the QAx, nQAx outputs are active. When LOW, the QAx, nQAx outputs are in a high impedance state. LVCMOS/LVTTL interface levels.
12	CLK	Input	Pulldown	Non-inverting differential clock input.
13	nCLK	Input	Pullup	Inverting differential clock input.
14	GND	Power		Power supply ground.
15	OEB	Input	Pullup	Output enable pin for QB0 pins. When HIGH, the QB0, nQB0 outputs are active. When LOW, the QB0, nQB0 outputs are in a high impedance state. LVCMOS/LVTTL interface levels.
17, 18	nQB0, QB0	Output		Differential output pair. LVDS interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

## **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ

## **Table 3. Output Enable Function Table**

Inputs	Outputs
OEx	Qx[0:1], nQx[0:1]
0	Hi-Impedance
1	Enabled

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics* or *AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>DD</sub>	4.6V
Inputs, V <sub>I</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, I <sub>O</sub>	
Continuos Current	10mA
Surge Current	15mA
Package Thermal Impedance, $\theta_{JA}$	86.7°C/W (0 mps)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

### **DC Electrical Characteristics**

Table 4A. LVDS Power Supply DC Characteristics,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{DD}$	Positive Supply Voltage		3.135	3.3	3.465	V
$V_{DDA}$	Analog Supply Voltage		V <sub>DD</sub> – 0.16	3.3	$V_{DD}$	V
$V_{DDO}$	Output Supply Voltage		3.135	3.3	3.465	V
I <sub>DD</sub>	Power Supply Current				74	mA
I <sub>DDA</sub>	Analog Supply Current				16	mA
I <sub>DDO</sub>	Output Supply Current				76	mA

### Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = V_{DDO} = 3.3 V \pm 5\%$ , $T_A = 0$ °C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V <sub>IH</sub>	Input High Voltage			2		V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage			-0.3		0.8	V
		OEA, OEB	$V_{DD} = V_{IN} = 3.465V$			5	μΑ
I <sub>IH</sub>	Input High Current	F_SEL0, F_SEL1, F_SEL2, MR	V <sub>DD</sub> = V <sub>IN</sub> = 3.465V			150	μΑ
		OEA, OEB	$V_{DD} = 3.465V, V_{IN} = 0V$	-150			μΑ
I <sub>IL</sub>	Input Low Current	F_SEL0, F_SEL1, F_SEL2, MR	V <sub>DD</sub> = 3.465V, V <sub>IN</sub> = 0V	-5			μΑ

Table 4C. Differential DC Characteristics,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
	Input High Current	CLK	$V_{DD} = V_{IN} = 3.465V$			150	μΑ
I IH	Input High Current	nCLK	$V_{DD} = V_{IN} = 3.465V$			5	μΑ
I <sub>IL</sub>	Input Low Current	CLK	$V_{DD} = 3.465V,$ $V_{IN} = 0V$	-5			μΑ
		nCLK	$V_{DD} = 3.465V,$ $V_{IN} = 0V$	-150			μΑ
V <sub>PP</sub>	Peak-to-Peak Voltage; NOTE 1			0.15		1.3	٧
V <sub>CMR</sub>	Common Mode Input Voltage; NOTE 1, 2			GND + 0.5		V <sub>DD</sub> – 0.85	٧

NOTE 1:  $V_{\text{IL}}$  should not be less than -0.3V.

NOTE 2: Common mode input voltage is defined as  $V_{IH}$ .

Table 4D. LVDS DC Characteristics,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OD</sub>	Differential Output Voltage		275	375	485	mV
$\Delta V_{OD}$	V <sub>OD</sub> Magnitude Change				50	mV
V <sub>OS</sub>	Offset Voltage		1.20	1.35	1.50	V
ΔV <sub>OS</sub>	V <sub>OS</sub> Magnitude Change				50	mV

Table 5. AC Characteristics,  $V_{DD} = V_{DDO} = 3.3V \pm 5\%$ ,  $T_A = 0$ °C to 70°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency		98		320	MHz
tjit(cc)	Cycle-to-Cycle Jitter; NOTE 1				35	ps
tsk(o)	Output Skew; NOTE 1, 2				135	ps
tsk(b)	Bank Skew; NOTE 1, 3	Bank A			50	ps
$t_R / t_F$	Output Rise/Fall Time	20% to 80%	215		550	ps
odc	Output Duty Cycle		47		53	%

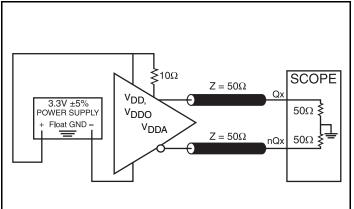
NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions.

NOTE 1: This parameter is defined in accordance with JEDEC Standard 65.

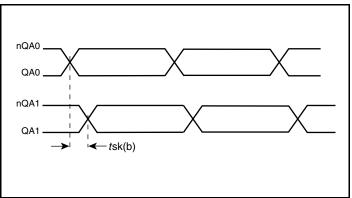
NOTE 2: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at the differential cross points.

NOTE 3: Defined as skew within a bank of outputs at the same voltage and with equal load conditions.

## **Parameter Measurement Information**



3.3V LVDS Output Load AC Test Circuit **Differential Input Level** 



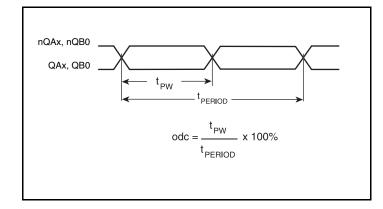
nQAx, nQB0 QAx, QB0 tjit(cc) = tcycle n – tcycle n+1 1000 Cycles

nQx - tsk(o)

**Cycle-to-Cycle Jitter** 

 $V_{DD}$  –

nCLK



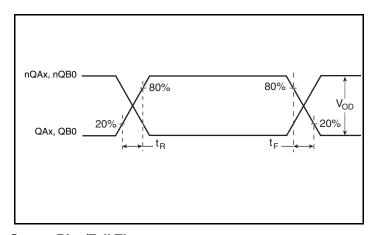
**Output Duty Cycle/Pulse Width/Period** 

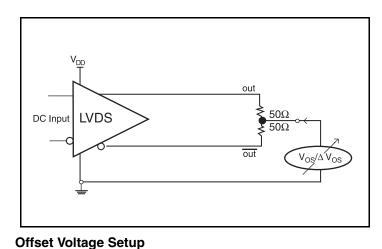
**Bank Skew** 

**Output Skew** 

ICS874003AG-04 REVISION B JANUARY 28, 2014

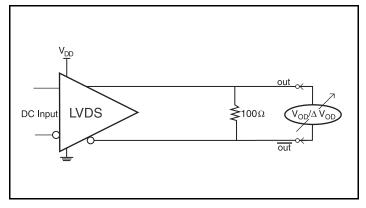
## **Parameter Measurement Information, continued**





**Output Rise/Fall Time** 

Oliset Voltage Setup



**Differential Output Voltage Setup** 

PCI EXPRESS™ JITTER ATTENUATOR

### **Application Information**

### **Power Supply Filtering Technique**

As in any high speed analog circuitry, the power supply pins are vulnerable to random noise. To achieve optimum jitter perform- ance, power supply isolation is required. The ICS874003-04 provides separate power supplies to isolate any high switching noise from the outputs to the internal PLL.  $V_{DD,}$   $V_{DDA}$  and  $V_{DDO}$  should be individually connected to the power supply plane through vias, and  $0.01\mu F$  bypass capacitors should be used for each pin. Figure 1 illustrates this for a generic  $V_{DD}$  pin and also shows that  $V_{DDA}$  requires that an additional  $10\Omega$  resistor along with a  $10\mu F$  bypass capacitor be connected to the  $V_{DDA}$  pin.

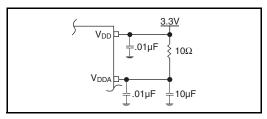


Figure 1. Power Supply Filtering

### Wiring the Differential Input to Accept Single-Ended Levels

Figure 2 shows how the differential input can be wired to accept single-ended levels. The reference voltage V\_REF =  $V_{DD}/2$  is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V\_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and  $V_{DD}$  = 3.3V, V\_REF should be 1.25V and R2/R1 = 0.609.

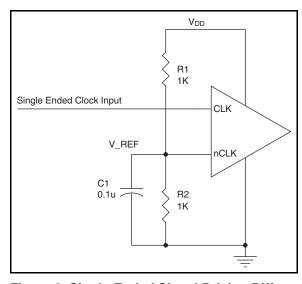
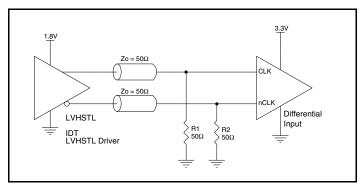


Figure 2. Single-Ended Signal Driving Differential Input

#### **Differential Clock Input Interface**

The CLK /nCLK accepts LVDS, LVPECL, LVHSTL, SSTL, HCSL and other differential signals. The differential signal must meet the  $V_{PP}$  and  $V_{CMR}$  input requirements. *Figures 3A to 3F* show interface examples for the HiPerClockS CLK/nCLK input driven by the most common driver types. The input interfaces suggested here are examples only. Please consult with the vendor of the driver

component to confirm the driver termination requirements. For example, in Figure 3A, the input termination applies for IDT HiPerClockS open emitter LVHSTL drivers. If you are using an LVHSTL driver from another vendor, use their termination recommendation.



3A. HiPerClockS CLK/nCLK Input Driven by an IDT Open Emitter HiPerClockS LVHSTL Driver

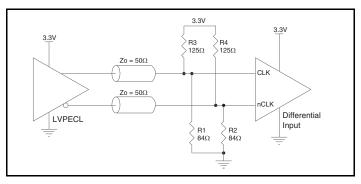


Figure 3C. HiPerClockS CLK/nCLK Input
Driven by a 3.3V LVPECL Driver

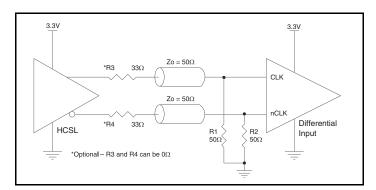


Figure 3E. HiPerClockS CLK/nCLK Input Driven by a 3.3V HCSL Driver

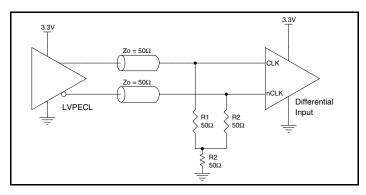


Figure 3B. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVPECL Driver

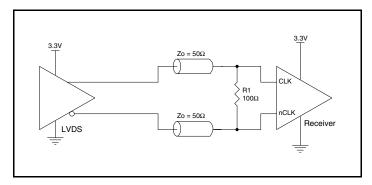


Figure 3D. HiPerClockS CLK/nCLK Input Driven by a 3.3V LVDS Driver

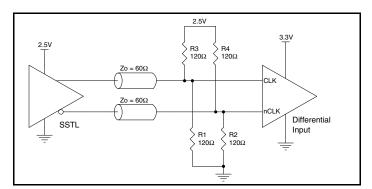


Figure 3F. HiPerClockS CLK/nCLK Input Driven by a 2.5V SSTL Driver

### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **LVCMOS Control Pins**

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1 \mathrm{k}\Omega$  resistor can be used.

### **Outputs:**

#### **LVDS Outputs**

All unused LVDS output pairs can be either left floating or terminated with 100 $\Omega$  across. If they are left floating, there should be no trace attached.

#### 3.3V LVDS Driver Termination

A general LVDS interface is shown in *Figure 4*. In a  $100\Omega$  differential transmission line environment, LVDS drivers require a matched load termination of  $100\Omega$  across near the receiver input. For a multiple

LVDS outputs buffer, if only partial outputs are used, it is recommended to terminate the unused outputs.

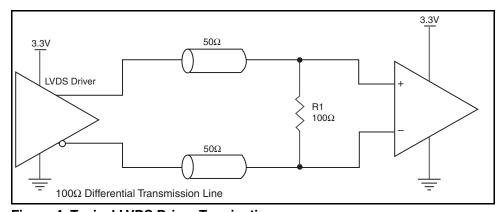


Figure 4. Typical LVDS Driver Termination

### **Schematic Example**

Figure 5 shows an example of ICS874003-04 application schematic. In this example, the device is operated at  $V_{DD} = 3.3V$ . The decoupling capacitors should be located as close as possible to the power pin.

Two examples of LVDS terminations are shown in this schematic. The input is driven either by a 3.3V LVPECL driver or a 3.3V LVCMOS.

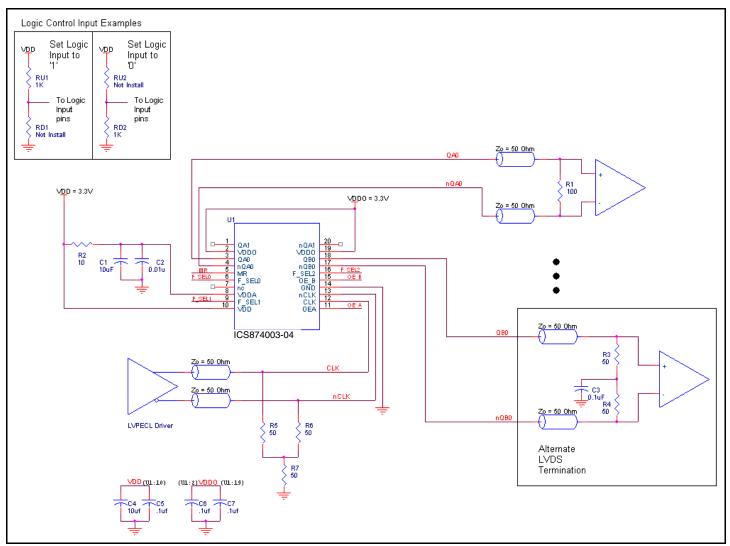


Figure 5. ICS874003-04 Schematic Example

#### **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS874003-04. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS74003-04 is the sum of the core power plus the analog power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 3.3V + 5\% = 3.465V$ , which gives worst case results.

- Power (core)<sub>MAX</sub> =  $V_{DD\_MAX}$  \* ( $I_{DD\_MAX}$  +  $I_{DDA\_MAX}$ ) = 3.465V \* (74mA + 16mA) = **311.85mW**
- Power (outputs)<sub>MAX</sub> = V<sub>DDO MAX</sub> \* I<sub>DDO MAX</sub> = 3.465V \* 76mA = 263.34mW

Total Power\_MAX = 311.85 mW + 263.34 mW = 575.19 mW

•

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C. Limiting the internal transistor junction temperature, Tj, to 125°C ensures that the bond wire and bond pad temperature remains below 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 86.7°C/W per Table 6 below.

Therefore, Ti for an ambient temperature of 70°C with all outputs switching is:

 $70^{\circ}\text{C} + 0.575\text{W} * 86.7^{\circ}\text{C/W} = 119.9^{\circ}\text{C}$ . This is well below the limit of  $125^{\circ}\text{C}$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (multi-layer).

Table 6. Thermal Resistance  $\theta_{JA}$  for 20 Lead TSSOP, Forced Convection

$\theta_{JA}$ by Velocity					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	86.7°C/W	82.4°C/W	80.2°C/W		

## **Reliability Information**

Table 7.  $\theta_{\text{JA}}$  vs. Air Flow Table for a 20 Lead TSSOP

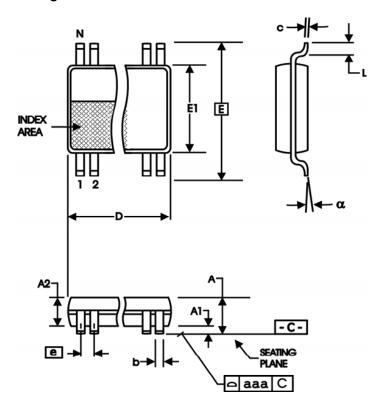
$\theta_{JA}$ by Velocity					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	86.7°C/W	82.4°C/W	80.2°C/W		

#### **Transistor Count**

The transistor count for ICS874003-04 is: 1,416

### **Package Outline and Package Dimensions**

Package Outline - G Suffix for 20 Lead TSSOP



**Table 8 Package Dimensions** 

All Dimensions in Millimeters						
Symbol	Minimum Maximu					
N	20					
Α		1.20				
A1	0.05	0.15				
A2	0.80	1.05				
b	0.19	0.30				
С	0.09	0.20				
D	6.40	6.60				
E	6.40 Basic					
E1	4.30	4.50				
е	0.65 Basic					
L	0.45	0.75				
α	0°	8°				
aaa		0.10				

Reference Document: JEDEC Publication 95, MO-153

# **Revision History Sheet**

Rev	Table	Page	Description of Change	
В			Product Discontinuation Notice - Last Time Buy Expires January 27, 2015, PDN# CQ-14-02	1/28/14

### **Ordering Information**

#### **Table 9. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
874003AG-04	ICS874003A04	20 Lead TSSOP	Tube	0°C to 70°C
874003AG-04T	ICS874003A04	20 Lead TSSOP	2500 Tape & Reel	0°C to 70°C
874003AG-04LF	ICS74003A04L	"Lead-Free" 20 Lead TSSOP	Tube	0°C to 70°C
874003AG-04LFT	ICS74003A04L	"Lead-Free" 20 Lead TSSOP	2500 Tape & Reel	0°C to 70°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

While the information presented herein has been checked for both accuracy and reliability, Integrated Device Technology (IDT) assumes no responsibility for either its use or for the infringement of any patents or other rights of third parties, which would result from its use. No other circuits, patents, or licenses are implied. This product is intended for use in normal commercial applications. Any other applications, such as those requiring extended temperature ranges, high reliability or other extraordinary environmental requirements are not recommended without additional processing by IDT. IDT reserves the right to change any circuitry or specifications without notice. IDT does not authorize or warrant any IDT product for use in life support devices or critical medical instruments.



6024 Silver Creek Valley Road San Jose, California 95138

800-345-7015 (inside USA) +408-284-8200 (outside USA) Fax: 408-284-2775

Sales

www.IDT.com/go/contactIDT

**Technical Support** 

 $\begin{array}{c} netcom@idt.com\\ +480\text{-}763\text{-}2056\end{array}$ 

DISCLAIMER Integrated Device Technology, Inc. (IDT) and its subsidiaries reserve the right to modify the products and/or specifications described herein at any time and at IDT's sole discretion. All information in this document, including descriptions of product features and performance, is subject to change without notice. Performance specifications and the operating parameters of the described products are determined in the independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are registered trademarks of IDT. Other trademarks and service marks used herein, including protected names, logos and designs, are the property of IDT or their respective third party owners.